

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10561830	HAYASHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Eoff Anca	1795

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
430	270.1, 326	5/7/2010	AE

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Updated search in EAST	5/7/2010	AE

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/A. E./  
Examiner.Art Unit 1795